SEARCH REQUEST, FORM Scientific and Technical Information Center - EIC2800 Rev. 1/26/2006 This is an experimental format -- Please give suggestions or comments to Jeff Harrison, JEF-4B68, 22511 3 Priority Application Date \9 Examiner # PAPER In what format would you like your results? Paper is the default. If submitting more than one search request form, please prioritize the searches in order of need. Where have you searched so far on this case? **IBM TDB** EPO Abs JPO Abs Circle: USPT DWPI Other: What relevant art have you found so far? Please attach citations or Information Disclosure Statements. What types of references would you like? Please checkmark: Nonpatent Literature Teaching Refs Primary Refs Other Secondary Refs Foreign Patents Is this a "Fast & Focused Search" request? (Circle One) YES A "Fast & Focused Search" is completed in 2-3 hours (maximum). The search must be on a very specific topic and meet certain criteria. The criteria are posted in EIC2800 and on the STIC NPL Web Page at http://uspto-a-pattr-2/siraapps/stic/npl/nplsearch.htm What is the topic, such as the novelty, motivation, utility, or other specific facets defining the desired focus of this search? Please include the concepts, synonyms, keywords, acronyms, registry numbers, definitions, structures, strategies, and anything else that helps to describe the topic. Please attach a copy of the abstract and pertinent claims Staff Use Only Type of Search Structure (#) Searcher Phone: Bibliographic\_ Dialog

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C-+	T	Description
Set	Items	
S1		PITCH??? OR CENTER (1N) CENTER OR CRITICAL () DIMENSION? ?
		R MINIMUM () LINE? ? OR MINIMUM () SPACE? ? OR SPACING? ? OR
	D	ENSIT??? OR SIZE? ? OR DENSE
S2	548686	SUBSTRATE? ? OR LAMINA? ? OR WAFER? ? OR DIE OR ARRAY? ?
s3	1794229	LEVEL? ? OR STACK???? OR LAYER???? OR FILM? ? OR LAMINA? ?
	0	R INTERLAYER???? OR MULTILAYER???? OR MULTI () LAYER????
S4	1233844	DEVICE? ? OR COMPONENT? ? OR TRANSISTOR? ?
S5	3053842	INCREASED OR HIGHER OR HIGH OR MORE OR GREATER OR LARGER
S6	4577	
s7	112152	S1 (2N) S5
S8	17438	S7 AND S2
S9	10358	S8 AND S3
S10	3161	S9 AND S4
S11	261	S10 AND PITCH
S12	154178	S3 (2N) (ABOVE OR HIGH OR SECOND OR TOP OR OVERHEAD OR
		UPPER OR PINNACLE)
S13	5496	S12 AND S7
S14	1755	S13 AND S2
S15	514	S14 AND S4
S16	44	S15 AND PITCH
S18	125	S12 AND PITCH AND DENSITY
S19	78	S18 AND S2
S20	45	S19 NOT S17
S21	17	S20 AND PY=1997:2003
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#2	Recent Search Queries			Results
#3		<u>#1</u>		404
#3		<u>#2</u>		91
42		<u>#3</u>		427
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		<u>#5</u>		81



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	Found:: :29 total   4 journal results   21 preferred web results   4 other web results	
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	Applied Physics, Mar 2003	capacitor
	area, and I the insulator thickness. As the lateral dimensions of the gate are decreased,	<u>dielectric</u>
	so as to increase the on-chip <b>device density</b> , the downward scaling for the gate dielectric layer thickness of below 2 nm for the field effect transistor is limited by	<u>embargo</u>
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	Laboratoire de magnétisme de Bretagne, BP 809, 29285 Brest, France Introduction In	wolverine .
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S1	68	S1:S11
S2	62	S1 AND PY=1990:2004
S3	19	S1 AND (DENSE OR DENSIT???)
S4	24	S2 AND (STACK??? OR MULTI () LAYER?? OR LEVEL? ?)
S5	15	S4 NOT S3